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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SCI, SPI
Peripherals	DMA, POR, PWM, WDT
Number of I/O	45
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 16
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/spc5602pef0mlh6r

1 Introduction

1.1 Document overview

This document provides electrical specifications, pin assignments, and package diagrams for the MPC5601P/2P series of microcontroller units (MCUs). It also describes the device features and highlights important electrical and physical characteristics. For functional characteristics, refer to the device reference manual.

1.2 Description

This 32-bit system-on-chip (SoC) automotive microcontroller family is the latest achievement in integrated automotive application controllers. It belongs to an expanding range of automotive-focused products designed to address chassis applications—specifically, electrical hydraulic power steering (EHPS) and electric power steering (EPS)—as well as airbag applications.

This family is one of a series of next-generation integrated automotive microcontrollers based on the Power Architecture® technology.

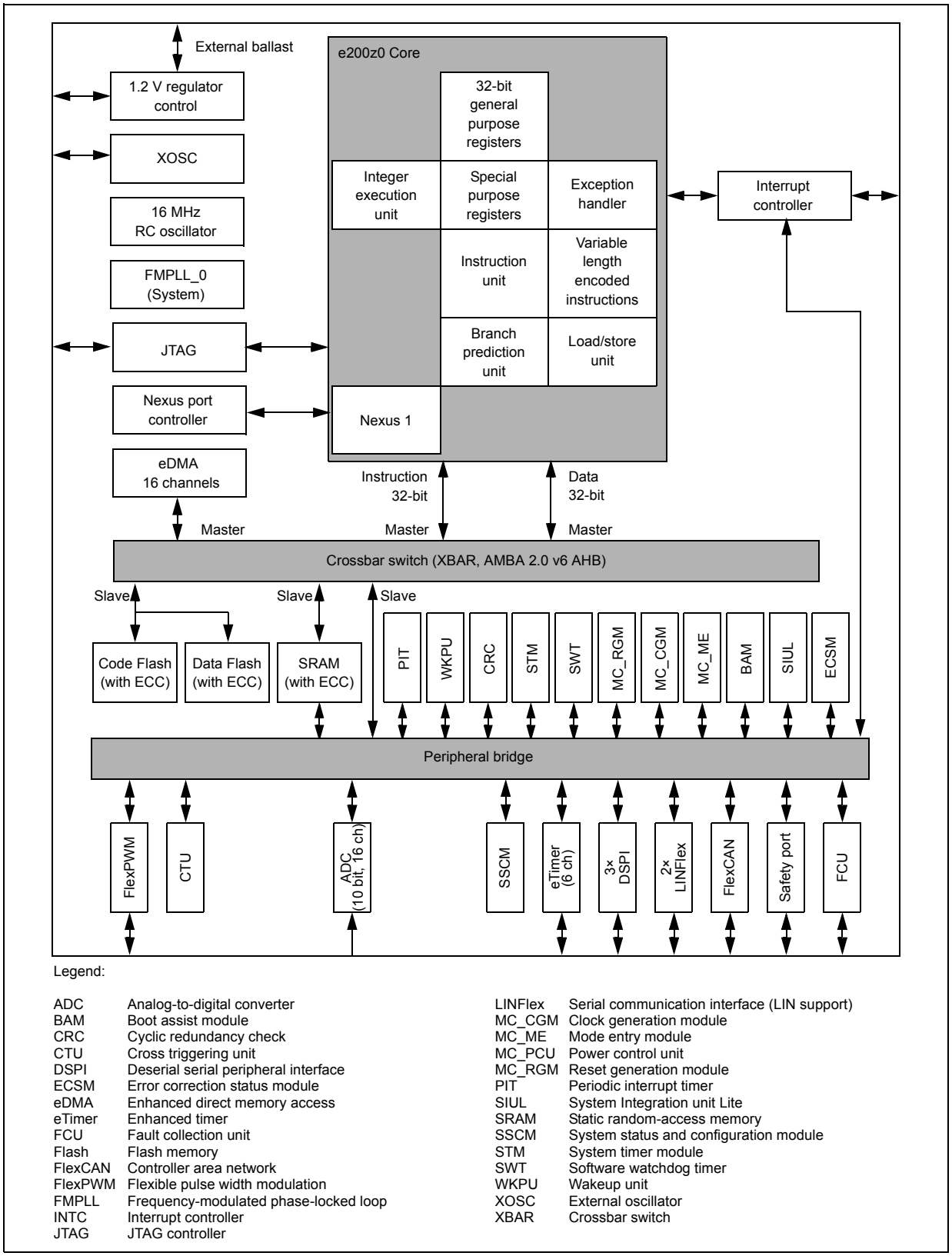
The advanced and cost-efficient host processor core of this automotive controller family complies with the Power Architecture embedded category. It operates at speeds of up to 64 MHz and offers high performance processing optimized for low power consumption. It capitalizes on the available development infrastructure of current Power Architecture devices and is supported with software drivers, operating systems and configuration code to assist with users implementations.

1.3 Device comparison

Table 1 provides a summary of different members of the MPC5602P family and their features to enable a comparison among the family members and an understanding of the range of functionality offered within this family.

Table 1. MPC5602P device comparison

Feature	MPC5601P	MPC5602P
Code flash memory (with ECC)	192 KB	256 KB
Data flash memory / EE option (with ECC)	64 KB (optional feature)	
SRAM (with ECC)	12 KB	20 KB
Processor core	32-bit e200z0h	
Instruction set	VLE (variable length encoding)	
CPU performance	0–64 MHz	
FMPLL (frequency-modulated phase-locked loop) module	1	
INTC (interrupt controller) channels	120	
PIT (periodic interrupt timer)	1 (with four 32-bit timers)	
eDMA (enhanced direct memory access) channels	16	
FlexCAN (controller area network)	1[1,2]	2[1,2]
Safety port	Yes (via FlexCAN module)	Yes (via second FlexCAN module)
FCU (fault collection unit)	Yes	
CTU (cross triggering unit)	No	Yes
eTimer	1 (16-bit, 6 channels)	



Legend:

ADC	Analog-to-digital converter
BAM	Boot assist module
CRC	Cyclic redundancy check
CTU	Cross triggering unit
DSPI	Deserial serial peripheral interface
ECSM	Error correction status module
eDMA	Enhanced direct memory access
eTimer	Enhanced timer
FCU	Fault collection unit
Flash	Flash memory
FlexCAN	Controller area network
FlexPWM	Flexible pulse width modulation
FMPLL	Frequency-modulated phase-locked loop
INTC	Interrupt controller
JTAG	JTAG controller
LINFlex	Serial communication interface (LIN support)
MC_CGM	Clock generation module
MC_ME	Mode entry module
MC_PCU	Power control unit
MC_RGM	Reset generation module
PIT	Periodic interrupt timer
SIUL	System Integration unit Lite
SRAM	Static random-access memory
SSCM	System status and configuration module
STM	System timer module
SWT	Software watchdog timer
WKPU	Wakeup unit
XOSC	External oscillator
XBAR	Crossbar switch

Figure 1. MPC5602P block diagram

lower priority ISRs do not delay the execution of higher priority ISRs. To allow the appropriate priorities for each source of interrupt request, the priority of each interrupt request is software configurable.

When multiple tasks share a resource, coherent accesses to that resource need to be supported. The INTC supports the priority ceiling protocol (PCP) for coherent accesses. By providing a modifiable priority mask, the priority can be raised temporarily so that all tasks which share the same resource can not preempt each other.

The INTC provides the following features:

- Unique 9-bit vector for each separate interrupt source
- 8 software triggerable interrupt sources
- 16 priority levels with fixed hardware arbitration within priority levels for each interrupt source
- Ability to modify the ISR or task priority: modifying the priority can be used to implement the priority ceiling protocol for accessing shared resources.
- 1 external high priority interrupt (NMI) directly accessing the main core and I/O processor (IOP) critical interrupt mechanism

1.5.7 System status and configuration module (SSCM)

The system status and configuration module (SSCM) provides central device functionality.

The SSCM includes these features:

- System configuration and status
  - Memory sizes/status
  - Device mode and security status
  - Determine boot vector
  - Search code flash for bootable sector
  - DMA status
- Debug status port enable and selection
- Bus and peripheral abort enable/disable

1.5.8 System clocks and clock generation

The following list summarizes the system clock and clock generation on the MPC5602P:

- Lock detect circuitry continuously monitors lock status
- Loss of clock (LOC) detection for PLL outputs
- Programmable output clock divider (÷1, ÷2, ÷4, ÷8)
- FlexPWM module and eTimer module running at the same frequency as the e200z0h core
- Internal 16 MHz RC oscillator for rapid start-up and safe mode: supports frequency trimming by user application

1.5.9 Frequency-modulated phase-locked loop (FMPLL)

The FMPLL allows the user to generate high speed system clocks from a 4–40 MHz input clock. Further, the FMPLL supports programmable frequency modulation of the system clock. The PLL multiplication factor, output clock divider ratio are all software configurable.

The FMPLL has the following major features:

- Input clock frequency: 4–40 MHz
- Maximum output frequency: 64 MHz
- Voltage controlled oscillator (VCO)—frequency 256–512 MHz
- Reduced frequency divider (RFD) for reduced frequency operation without forcing the FMPLL to relock

- Programmable selection of reset or interrupt on an initial time-out
- Master access protection
- Hard and soft configuration lock bits
- Reset configuration inputs allow timer to be enabled out of reset

1.5.15 Fault collection unit (FCU)

The FCU provides an independent fault reporting mechanism even if the CPU is malfunctioning.

The FCU module has the following features:

- FCU status register reporting the device status
- Continuous monitoring of critical fault signals
- User selection of critical signals from different fault sources inside the device
- Critical fault events trigger 2 external pins (user selected signal protocol) that can be used externally to reset the device and/or other circuitry (for example, a safety relay)
- Faults are latched into a register

1.5.16 System integration unit – Lite (SIUL)

The MPC5602P SIUL controls MCU pad configuration, external interrupt, general purpose I/O (GPIO), and internal peripheral multiplexing.

The pad configuration block controls the static electrical characteristics of I/O pins. The GPIO block provides uniform and discrete input/output control of the I/O pins of the MCU.

The SIUL provides the following features:

- Centralized general purpose input output (GPIO) control of up to 49 input/output pins and 16 analog input-only pads (package dependent)
- All GPIO pins can be independently configured to support pull-up, pull-down, or no pull
- Reading and writing to GPIO supported both as individual pins and 16-bit wide ports
- All peripheral pins, except ADC channels, can be alternatively configured as both general purpose input or output pins
- ADC channels support alternative configuration as general purpose inputs
- Direct readback of the pin value is supported on all pins through the SIUL
- Configurable digital input filter that can be applied to some general purpose input pins for noise elimination
- Up to 4 internal functions can be multiplexed onto 1 pin

1.5.17 Boot and censorship

Different booting modes are available in the MPC5602P: booting from internal flash memory and booting via a serial link.

The default booting scheme uses the internal flash memory (an internal pull-down resistor is used to select this mode). Optionally, the user can boot via FlexCAN or LINFlex (using the boot assist module software).

A censorship scheme is provided to protect the content of the flash memory and offer increased security for the entire device.

A password mechanism is designed to grant the legitimate user access to the non-volatile memory.

1.5.17.1 Boot assist module (BAM)

The BAM is a block of read-only memory that is programmed once and is identical for all MPC560xP devices that are based on the e200z0h core. The BAM program is executed every time the device is powered on if the alternate boot mode has been selected by the user.

The BAM provides the following features:

- Serial bootloading via FlexCAN or LINFlex
- Ability to accept a password via the used serial communication channel to grant the legitimate user access to the non-volatile memory

1.5.18 Error correction status module (ECSM)

The ECSM provides a myriad of miscellaneous control functions regarding program-visible information about the platform configuration and revision levels, a reset status register, a software watchdog timer, wakeup control for exiting sleep modes, and information on platform memory errors reported by error-correcting codes and/or generic access error information for certain processor cores.

The Error Correction Status Module supports a number of miscellaneous control functions for the platform. The ECSM includes these features:

- Registers for capturing information on platform memory errors if error-correcting codes (ECC) are implemented
- For test purposes, optional registers to specify the generation of double-bit memory errors are enabled on the MPC5602P.

The sources of the ECC errors are:

- Flash memory
- SRAM

1.5.19 Peripheral bridge (PBRIDGE)

The PBRIDGE implements the following features:

- Duplicated periphery
- Master access privilege level per peripheral (per master: read access enable; write access enable)
- Write buffering for peripherals
- Checker applied on PBRIDGE output toward periphery
- Byte endianess swap capability

1.5.20 Controller area network (FlexCAN)

The MPC5602P MCU contains one controller area network (FlexCAN) module. This module is a communication controller implementing the CAN protocol according to Bosch Specification version 2.0B. The CAN protocol was designed to be used primarily as a vehicle serial data bus, meeting the specific requirements of this field: real-time processing, reliable operation in the EMI environment of a vehicle, cost-effectiveness and required bandwidth. The FlexCAN module contains 32 message buffers.

The FlexCAN module provides the following features:

- Full implementation of the CAN protocol specification, version 2.0B
  - Standard data and remote frames
  - Extended data and remote frames
  - Up to 8-bytes data length
  - Programmable bit rate up to 1 Mbit/s
- 32 message buffers of up to 8-bytes data length
- Each message buffer configurable as Rx or Tx, all supporting standard and extended messages
- Programmable loop-back mode supporting self-test operation
- 3 programmable mask registers

- Trigger generation unit configurable in sequential mode or in triggered mode
- Each trigger can be appropriately delayed to compensate the delay of external low pass filter
- Double buffered global trigger unit allowing eTimer synchronization and/or ADC command generation
- Double buffered ADC command list pointers to minimize ADC-trigger unit update
- Double buffered ADC conversion command list with up to 24 ADC commands
- Each trigger capable of generating consecutive commands
- ADC conversion command allows to control ADC channel, single or synchronous sampling, independent result queue selection

1.5.28 Nexus Development Interface (NDI)

The NDI (Nexus Development Interface) block is compliant with Nexus Class 1 of the IEEE-ISTO 5001-2003 standard. This development support is supplied for MCUs without requiring external address and data pins for internal visibility. The NDI block is an integration of several individual Nexus blocks that are selected to provide the development support interface for this device. The NDI block interfaces to the host processor and internal busses to provide development support as per the IEEE-ISTO 5001-2003 Nexus Class 1 standard. The development support provided includes access to the MCU's internal memory map and access to the processor's internal registers.

The NDI provides the following features:

- Configured via the IEEE 1149.1
- All Nexus port pins operate at V_{DDIO} (no dedicated power supply)
- Nexus Class 1 supports Static debug

1.5.29 Cyclic redundancy check (CRC)

The CRC computing unit is dedicated to the computation of CRC off-loading the CPU. The CRC module features:

- Support for CRC-16-CCITT ($x25$ protocol):
  - $x^{16} + x^{12} + x^5 + 1$
- Support for CRC-32 (Ethernet protocol):
  - $x^{32} + x^{26} + x^{23} + x^{22} + x^{16} + x^{12} + x^{11} + x^{10} + x^8 + x^7 + x^5 + x^4 + x^2 + x + 1$
- Zero wait states for each write/read operations to the CRC_CFG and CRC_INP registers at the maximum frequency

1.5.30 IEEE 1149.1 JTAG controller

The JTAG controller (JTAGC) block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

The JTAG controller provides the following features:

- IEEE test access port (TAP) interface 4 pins (TDI, TMS, TCK, TDO)
- Selectable modes of operation include JTAGC/debug or normal system operation.
- 5-bit instruction register that supports the following IEEE 1149.1-2001 defined instructions:
  - BYPASS
  - IDCODE
  - EXTEST
  - SAMPLE
  - SAMPLE/PRELOAD
- 5-bit instruction register that supports the additional following public instructions:
  - ACCESS_AUX_TAP_NPC

2.2.2 System pins

Table 4 and Table 5 contain information on pin functions for the MPC5602P devices. The pins listed in Table 4 are single-function pins. The pins shown in Table 5 are multi-function pins, programmable via their respective pad configuration register (PCR) values.

Table 4. System pins

Symbol	Description	Direction	Pad speed[1]		Pin	
			SRC = 0	SRC = 1	64-pin	100-pin
Dedicated pins						
NMI	Non-maskable Interrupt	Input only	Slow	—	1	1
XTAL	Analog output of the oscillator amplifier circuit—needs to be grounded if oscillator is used in bypass mode	—	—	—	11	18
EXTAL	Analog input of the oscillator amplifier circuit, when the oscillator is not in bypass mode Analog input for the clock generator when the oscillator is in bypass mode	—	—	—	12	19
TDI	JTAG test data input	Input only	Slow	—	35	58
TMS	JTAG state machine control	Input only	Slow	—	36	59
TCK	JTAG clock	Input only	Slow	—	37	60
TDO	JTAG test data output	Output only	Slow	Fast	38	61
Reset pin						
$\overline{\text{RESET}}$	Bidirectional reset with Schmitt trigger characteristics and noise filter	Bidirectional	Medium	—	13	20
Test pin						
VPP_TEST	Pin for testing purpose only. To be tied to ground in normal operating mode.	—	—	—	47	74

1 SRC values refer to the value assigned to the Slew Rate Control bits of the pad configuration register.

2.2.3 Pin multiplexing

Table 5 defines the pin list and muxing for the MPC5602P devices.

Each row of Table 5 shows all the possible ways of configuring each pin, via alternate functions. The default function assigned to each pin after reset is the ALT0 function.

MPC5602P devices provide three main I/O pad types, depending on the associated functions:

- *Slow pads* are the most common, providing a compromise between transition time and low electromagnetic emission.
- *Medium pads* provide fast enough transition for serial communication channels with controlled current to reduce electromagnetic emission.
- *Fast pads* provide maximum speed. They are used for improved NEXUS debugging capability.

Medium and Fast pads can use slow configuration to reduce electromagnetic emission, at the cost of reducing AC performance. For more information, see “Pad AC Specifications” in the device data sheet.

Table 5. Pin muxing (continued)

Port pin	PCR register	Alternate function[1,2]	Functions	Peripheral[3]	I/O direction[4]	Pad speed[5]		Pin	
						SRC = 0	SRC = 1	64-pin	100-pin
D[4]	PCR[52]	ALT0 ALT1 ALT2 ALT3	GPIO[52] — — B[3]	SIUL — — FlexPWM_0	I/O — — O	Slow	Medium	—	90
D[5]	PCR[53]	ALT0 ALT1 ALT2 ALT3	GPIO[53] CS3 F[0] —	SIUL DSPI_0 FCU_0 —	I/O O O —	Slow	Medium	—	22
D[6]	PCR[54]	ALT0 ALT1 ALT2 ALT3 —	GPIO[54] CS2 — — FAULT[1]	SIUL DSPI_0 — — FlexPWM_0	I/O O — — I	Slow	Medium	—	23
D[7]	PCR[55]	ALT0 ALT1 ALT2 ALT3	GPIO[55] CS3 F[1] CS4	SIUL DSPI_1 FCU_0 DSPI_0	I/O O O O	Slow	Medium	17	26
D[8]	PCR[56]	ALT0 ALT1 ALT2 ALT3	GPIO[56] CS2 — CS5	SIUL DSPI_1 — DSPI_0	I/O O — O	Slow	Medium	14	21
D[9]	PCR[57]	ALT0 ALT1 ALT2 ALT3	GPIO[57] X[0] TXD —	SIUL FlexPWM_0 LIN_1 —	I/O O O —	Slow	Medium	8	15
D[10]	PCR[58]	ALT0 ALT1 ALT2 ALT3	GPIO[58] A[0] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	—	53
D[11]	PCR[59]	ALT0 ALT1 ALT2 ALT3	GPIO[59] B[0] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	—	54
D[12]	PCR[60]	ALT0 ALT1 ALT2 ALT3 —	GPIO[60] X[1] — — RXD	SIUL FlexPWM_0 — — LIN_1	I/O O — — I	Slow	Medium	45	70
D[13]	PCR[61]	ALT0 ALT1 ALT2 ALT3	GPIO[61] A[1] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	44	67
D[14]	PCR[62]	ALT0 ALT1 ALT2 ALT3	GPIO[62] B[1] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	46	73

3 Electrical characteristics

3.1 Introduction

This section contains device electrical characteristics as well as temperature and power considerations.

This microcontroller contains input protection against damage due to high static voltages. However, it is advisable to take precautions to avoid application of any voltage higher than the specified maximum rated voltages.

To enhance reliability, unused inputs can be driven to an appropriate logic voltage level (V_{DD} or V_{SS}). This can be done by the internal pull-up or pull-down resistors, which are provided by the device for most general purpose pins.

The following tables provide the device characteristics and its demands on the system.

In the tables where the device logic provides signals with their respective timing characteristics, the symbol “CC” for Controller Characteristics is included in the Symbol column.

In the tables where the external system must provide signals with their respective timing characteristics to the device, the symbol “SR” for System Requirement is included in the Symbol column.

CAUTION

All of the following parameter values can vary depending on the application and must be confirmed during silicon characterization or silicon reliability trial.

3.2 Parameter classification

The electrical parameters are guaranteed by various methods. To give the customer a better understanding, the classifications listed in Table 6 are used and the parameters are tagged accordingly in the tables where appropriate.

Table 6. Parameter classifications

Classification tag	Tag description
P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

3.3 Absolute maximum ratings

Table 7. Absolute maximum ratings[1]

Symbol		Parameter	Conditions	Value		Unit
				Min	Max	
V_{SS}	SR	Device ground	—	0	0	V

1 Functional operating conditions are given in the DC electrical characteristics. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the listed maxima may affect device reliability or cause permanent damage to the device.

2 The difference between each couple of voltage supplies must be less than 300 mV, $|V_{DD\_HV\_IOy} - V_{DD\_HV\_IOx}| < 300$ mV.

3 Guaranteed by device validation.

4 Minimum value of TV_{DD} must be guaranteed until $V_{DD\_HV\_REG}$ reaches 2.6 V (maximum value of V_{PORH})

5 Only when $V_{DD\_HV\_IOx} < 5.2$ V

Figure 4 shows the constraints of the different power supplies.

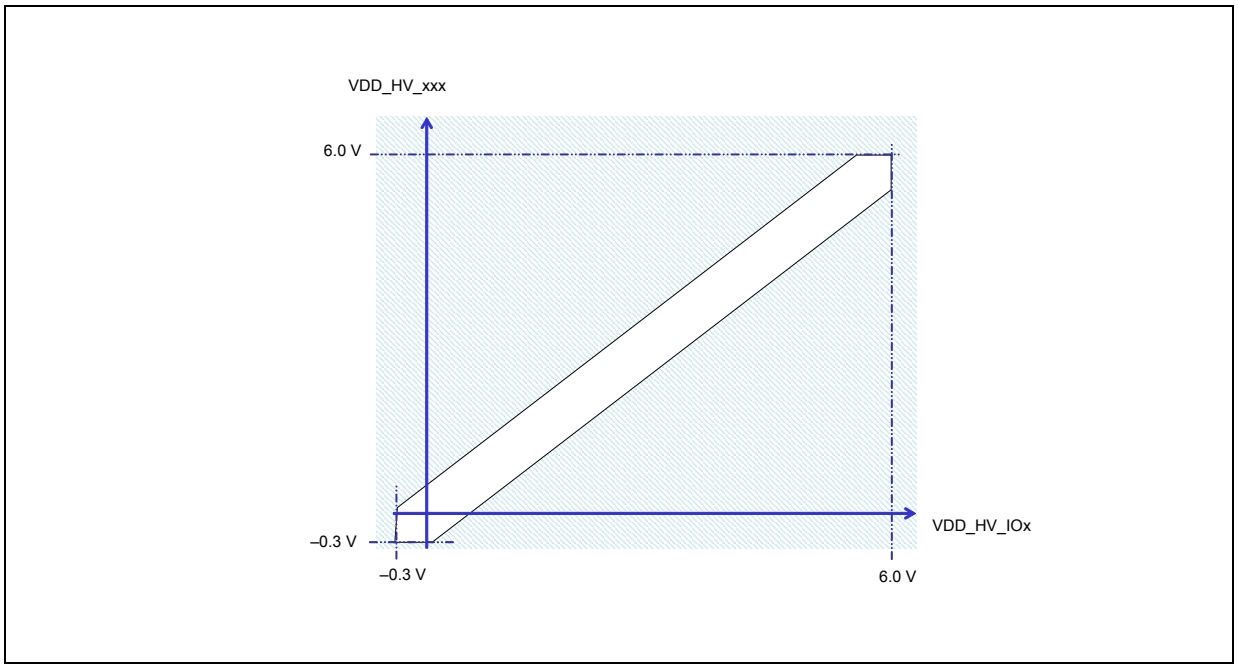


Figure 4. Power supplies constraints (–0.3 V ≤ $V_{DD\_HV\_IOx}$ ≤ 6.0 V)

The MPC5602P supply architecture allows the ADC supply to be managed independently from the standard V_{DD_HV} supply. Figure 5 shows the constraints of the ADC power supply.

- LVDLVCOR monitors low voltage digital power domain

Table 15. Low voltage monitor electrical characteristics

Symbol	C	Parameter	Conditions[1]	Value		Unit
				Min	Max	
V_{PORH}	T	Power-on reset threshold	—	1.5	2.7	V
V_{PORUP}	P	Supply for functional POR module	T_A = 25 °C	1.0	—	V
$V_{REGLVDMOK\_H}$	P	Regulator low voltage detector high threshold	—	—	2.95	V
$V_{REGLVDMOK\_L}$	P	Regulator low voltage detector low threshold	—	2.6	—	V
$V_{FLLVDMOK\_H}$	P	Flash low voltage detector high threshold	—	—	2.95	V
$V_{FLLVDMOK\_L}$	P	Flash low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDMOK\_H}$	P	I/O low voltage detector high threshold	—	—	2.95	V
$V_{IOLVDMOK\_L}$	P	I/O low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDM5OK\_H}$	P	I/O 5 V low voltage detector high threshold	—	—	4.4	V
$V_{IOLVDM5OK\_L}$	P	I/O 5 V low voltage detector low threshold	—	3.8	—	V
$V_{MLVDDOK\_H}$	P	Digital supply low voltage detector high	—	—	1.145	V
$V_{MLVDDOK\_L}$	P	Digital supply low voltage detector low	—	1.08	—	V

[1] V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 °C to $T_{A\ MAX}$, unless otherwise specified

3.9 Power up/down sequencing

To prevent an overstress event or a malfunction within and outside the device, the MPC5602P implements the following sequence to ensure each module is started only when all conditions for switching it ON are available:

- A POWER_ON module working on voltage regulator supply controls the correct start-up of the regulator. This is a key module ensuring safe configuration for all voltage regulator functionality when supply is below 1.5 V. Associated POWER_ON (or POR) signal is active low.
- Several low voltage detectors, working on voltage regulator supply monitor the voltage of the critical modules (voltage regulator, I/Os, flash memory and low voltage domain). LVDs are gated low when POWER_ON is active.
- A POWER_OK signal is generated when all critical supplies monitored by the LVD are available. This signal is active high and released to all modules including I/Os, flash memory and 16 MHz RC oscillator needed during power-up phase and reset phase. When POWER_OK is low the associated modules are set into a safe state.

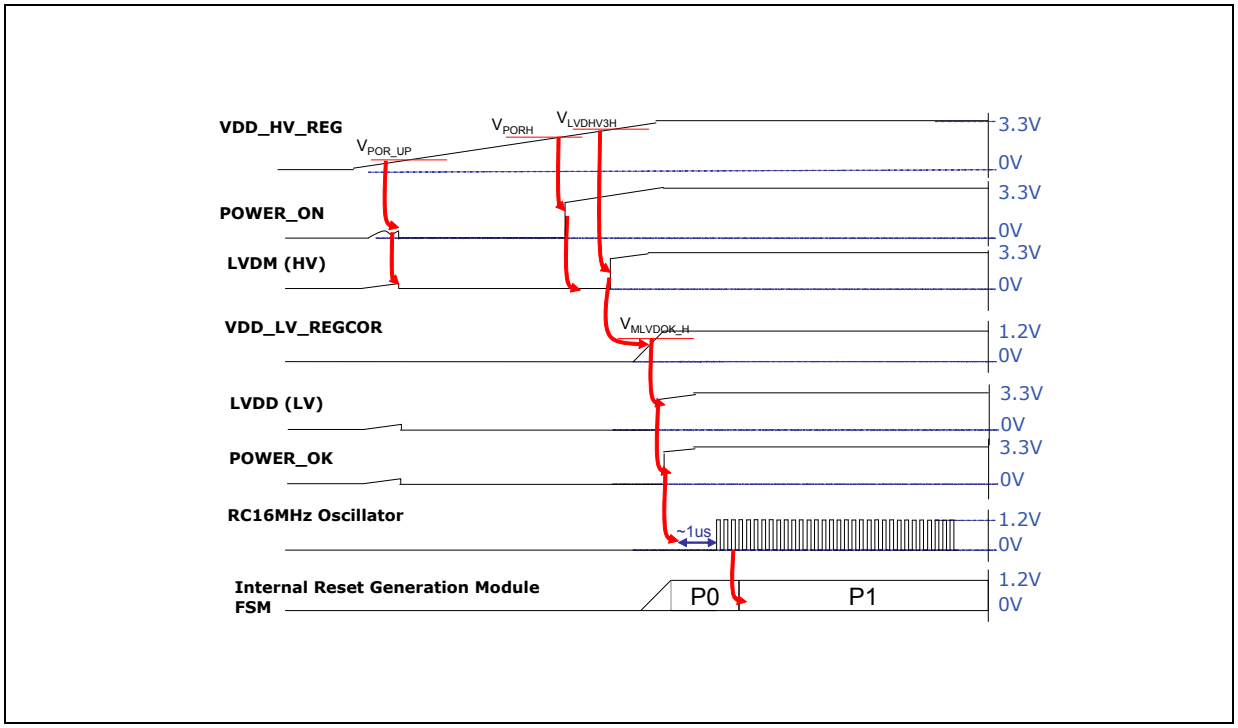


Figure 9. Power-up typical sequence

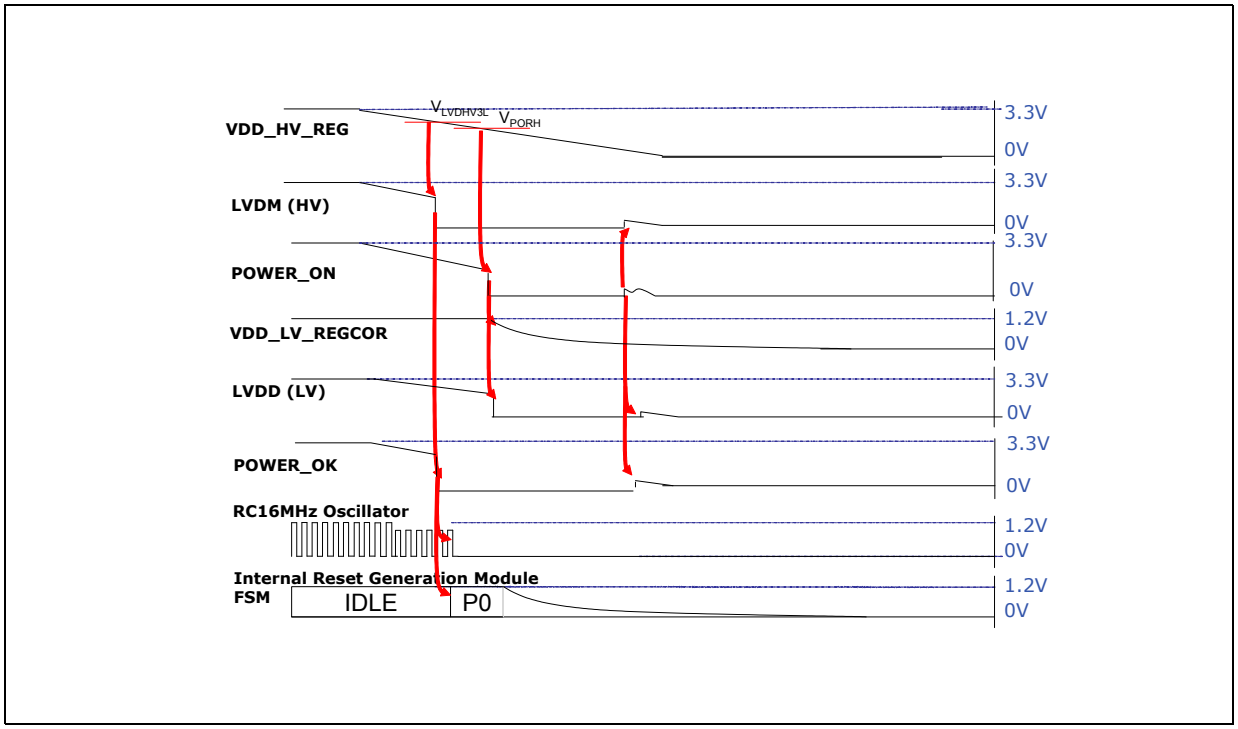
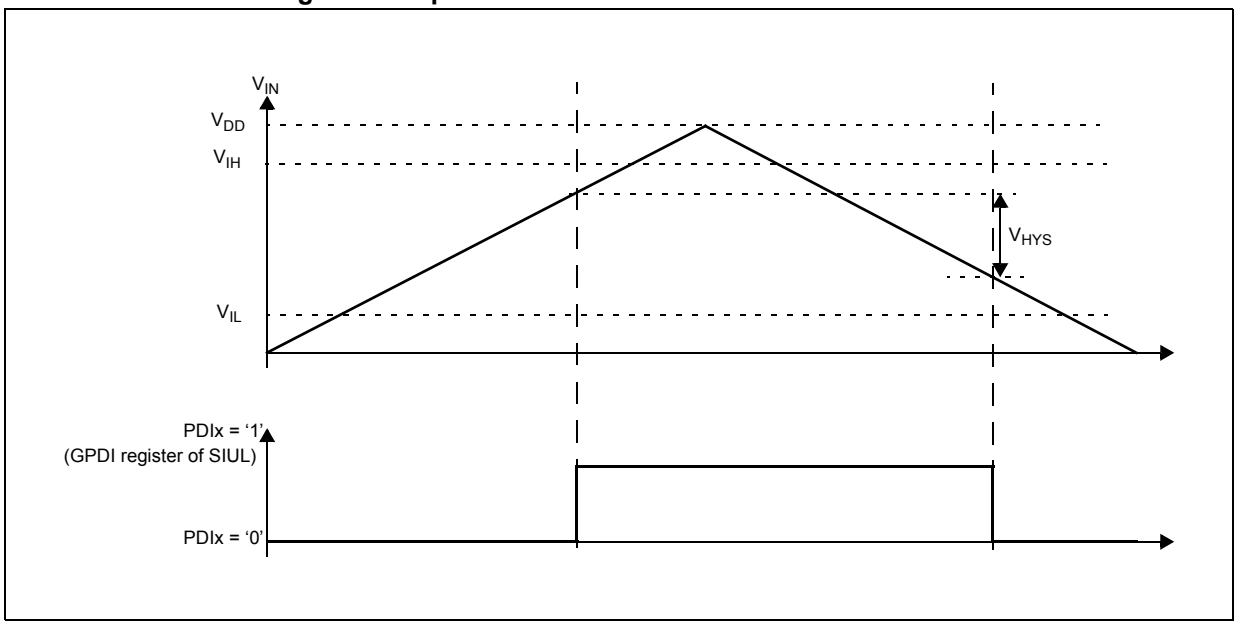


Figure 10. Power-down typical sequence

3.10.4 Input DC electrical characteristics definition

Figure 12 shows the DC electrical characteristics behavior as function of time.

Figure 12. Input DC electrical characteristics definition



3.10.5 I/O pad current specification

The I/O pads are distributed across the I/O supply segment. Each I/O supply segment is associated to a V_{DD}/V_{SS} supply pair as described in Table 21.

Table 21. I/O supply segment

Package	Supply segment				
	1	2	3	4	5
100 LQFP	pin15–pin26	pin27–pin46	pin51–pin61	pin64–pin86	pin89–pin10
64 LQFP	pin8–pin17	pin18–pin30	pin33–pin38	pin41–pin54	pin57–pin5

Table 22. I/O consumption

Symbol		C	Parameter	Conditions[1]		Value			Unit
						Min	Typ	Max	
I_{SWTSLW}[2]	CC	D	Dynamic I/O current for SLOW configuration	C_L = 25 pF	V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	20	mA
					V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	16	
I_{SWTMED}(2)	CC	D	Dynamic I/O current for MEDIUM configuration	C_L = 25 pF	V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	29	mA
					V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	17	

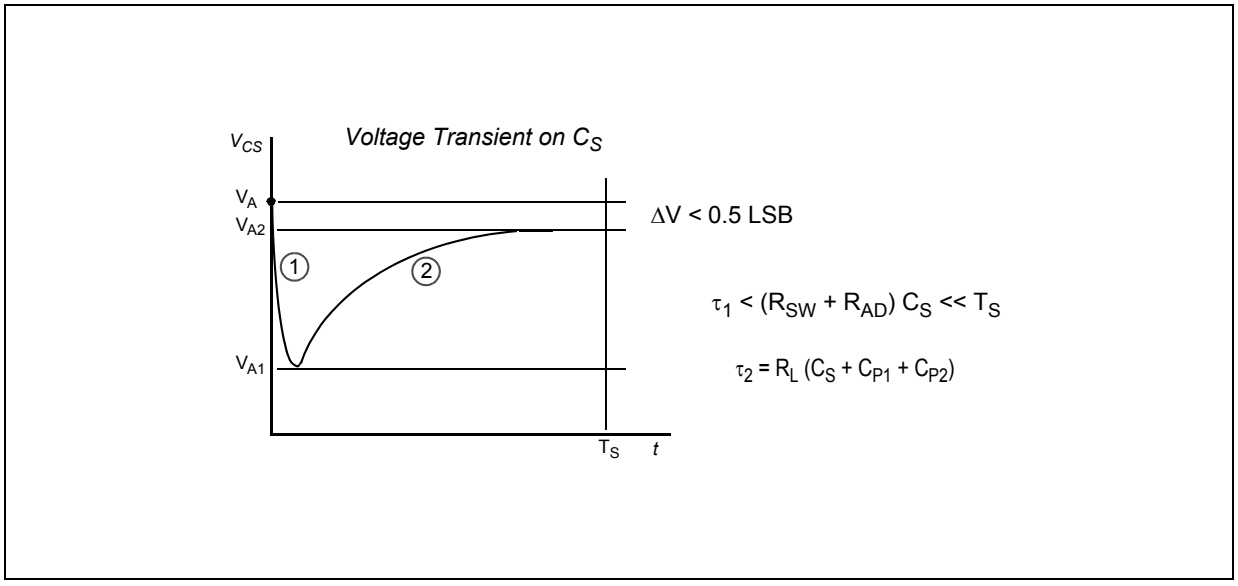


Figure 15. Transient behavior during sampling phase

In particular two different transient periods can be distinguished:

- A first and quick charge transfer from the internal capacitance C_{P1} and C_{P2} to the sampling capacitance C_S occurs (C_S is supposed initially completely discharged): considering a worst case (since the time constant in reality would be faster) in which C_{P2} is reported in parallel to C_{P1} (call $C_P = C_{P1} + C_{P2}$), the two capacitances C_P and C_S are in series, and the time constant is

Eqn. 5

$$\tau_1 = (R_{SW} + R_{AD}) \bullet \frac{C_P \bullet C_S}{C_P + C_S}$$

Equation 5 can again be simplified considering only C_S as an additional worst condition. In reality, the transient is faster, but the A/D converter circuitry has been designed to be robust also in the very worst case: the sampling time T_S is always much longer than the internal time constant:

Eqn. 6

$$\tau_1 < (R_{SW} + R_{AD}) \bullet C_S \ll T_S$$

The charge of C_{P1} and C_{P2} is redistributed also on C_S, determining a new value of the voltage V_{A1} on the capacitance according to Equation 7:

Eqn. 7

$$V_{A1} \bullet (C_S + C_{P1} + C_{P2}) = V_A \bullet (C_{P1} + C_{P2})$$

- A second charge transfer involves also C_F (that is typically bigger than the on-chip capacitance) through the resistance R_L: again considering the worst case in which C_{P2} and C_S were in parallel to C_{P1} (since the time constant in reality would be faster), the time constant is:

Eqn. 8

$$\tau_2 < R_L \bullet (C_S + C_{P1} + C_{P2})$$

Table 35. $\overline{\text{RESET}}$ electrical characteristics

Symbol		C	Parameter	Conditions[1]	Value[2]			Unit
					Min	Typ	Max	
V_{IH}	SR	P	Input high level CMOS (Schmitt Trigger)	—	$0.65V_{DD}$	—	V_{DD} + 0.4	V
V_{IL}	SR	P	Input low level CMOS (Schmitt Trigger)	—	–0.4	—	$0.35V_{DD}$	V
V_{HYS}	CC	C	Input hysteresis CMOS (Schmitt Trigger)	—	$0.1V_{DD}$	—	—	V
V_{OL}	CC	P	Output low level	Push Pull, I_{OL} = 2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	—	—	$0.1V_{DD}$	V
				Push Pull, I_{OL} = 1 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 1[3]	—	—	$0.1V_{DD}$	
				Push Pull, I_{OL} = 1 mA, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)	—	—	0.5	
t_{tr}	CC	D	Output transition time output pin[4] MEDIUM configuration	C_L = 25 pF, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	10	ns
				C_L = 50 pF, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	20	
				C_L = 100 pF, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	40	
				C_L = 25 pF, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	12	
				C_L = 50 pF, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	25	
				C_L = 100 pF, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	40	
W_{FRST}	SR	P	$\overline{\text{RESET}}$ input filtered pulse	—	—	—	40	ns
W_{NFRST}	SR	P	$\overline{\text{RESET}}$ input not filtered pulse	—	500	—	—	ns
t_{POR}	CC	D	Maximum delay before internal reset is released after all V_{DD_HV} reach nominal supply	Monotonic V_{DD_HV} supply ramp	—	—	1	ms
$\lvert I_{WPU} \rvert$	CC	P	Weak pull-up current absolute value	V_{DD} = 3.3 V ± 10%, PAD3V5V = 1	10	—	150	µA
				V_{DD} = 5.0 V ± 10%, PAD3V5V = 0	10	—	150	
				V_{DD} = 5.0 V ± 10%, PAD3V5V = 1[5]	10	—	250	

1 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

2 All values need to be confirmed during device validation.

3 This is a transient configuration during power-up, up to the end of reset PHASE2 (refer to RGM module section of device reference manual).

[1] All Nexus timing relative to MCKO is measured from 50% of MCKO and 50% of the respective signal.
[2] Lower frequency is required to be fully compliant to standard.

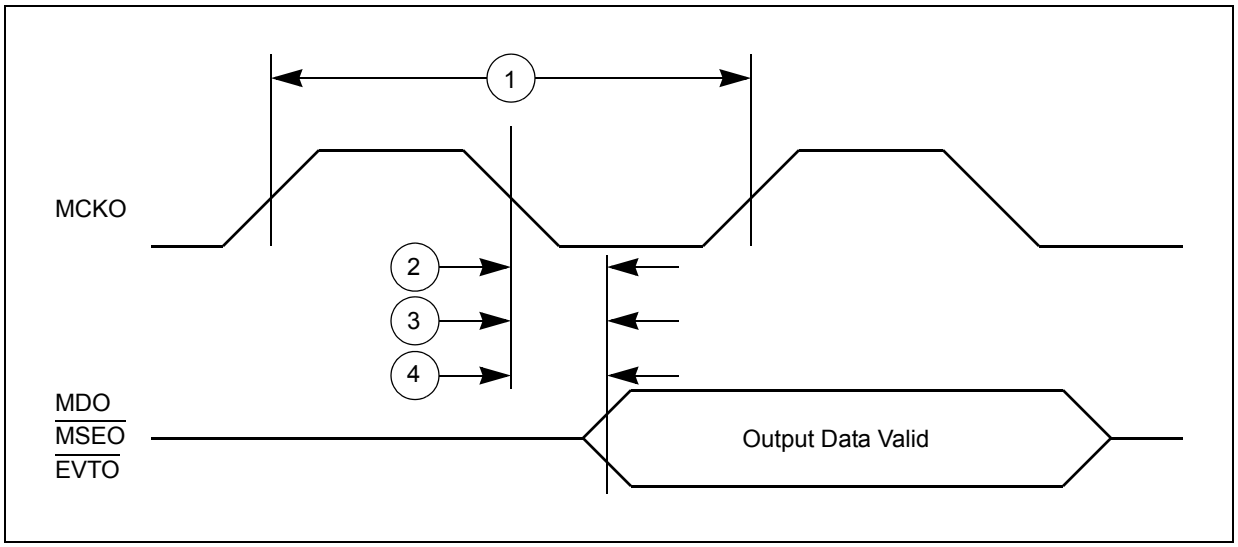


Figure 23. Nexus output timing

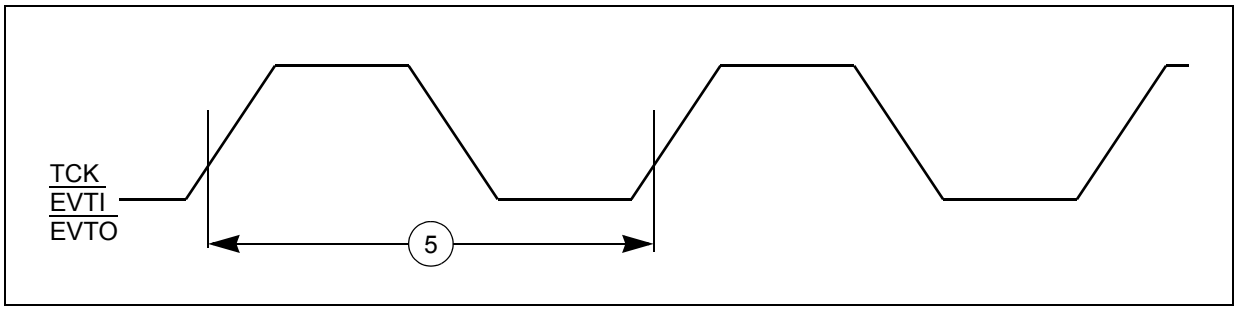


Figure 24. Nexus event trigger and test clock timing

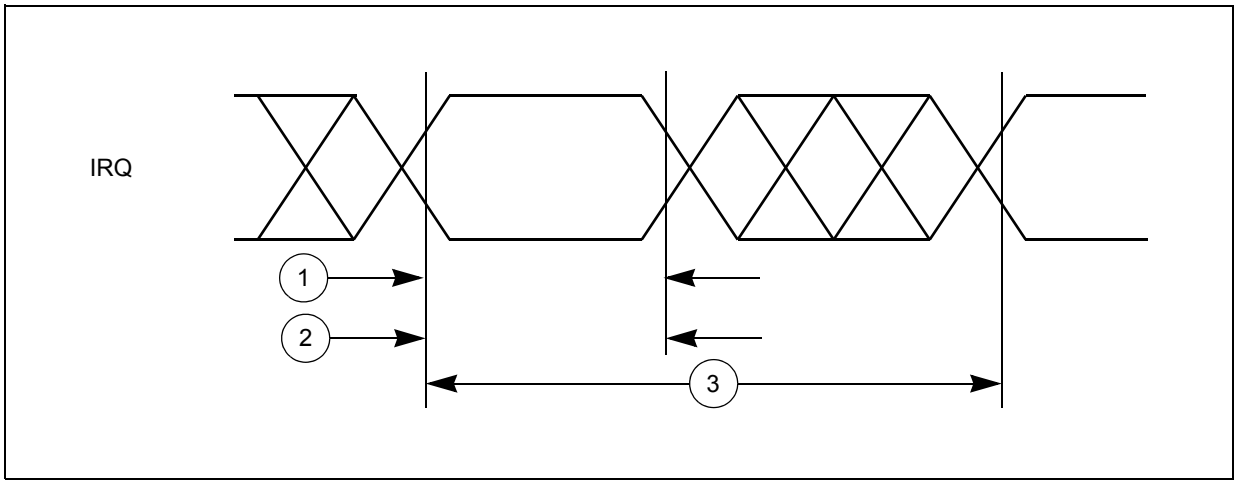
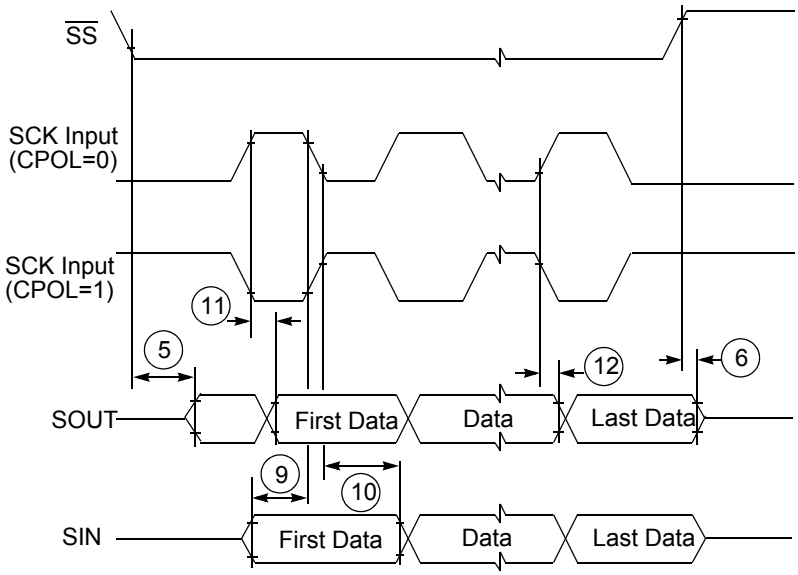


Figure 26. External interrupt timing

3.17.5 DSPI timing

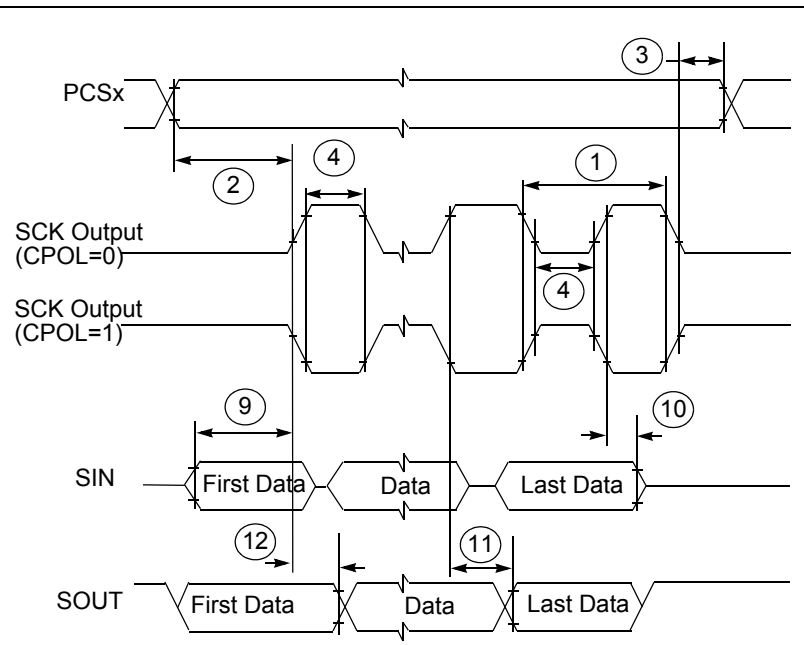
Table 39. DSPI timing[1]

No.	Symbol		C	Parameter	Conditions	Value		Unit
						Min	Max	
1	t_{SCK}	CC	D	DSPI cycle time	Master (MTFE = 0)	60	—	ns
					Slave (MTFE = 0)	60	—	
2	t_{CSC}	CC	D	CS to SCK delay	—	16	—	ns
3	t_{ASC}	CC	D	After SCK delay	—	26	—	ns
4	t_{SDC}	CC	D	SCK duty cycle	—	0.4 * t_{SCK}	0.6 * t_{SCK}	ns
5	t_A	CC	D	Slave access time	$\overline{SS}$ active to SOUT valid	—	30	ns
6	t_{DIS}	CC	D	Slave SOUT disable time	$\overline{SS}$ inactive to SOUT high impedance or invalid	—	16	ns
7	t_{PCSC}	CC	D	PCSx to $\overline{PCSS}$ time	—	13	—	ns
8	t_{PASC}	CC	D	$\overline{PCSS}$ to PCSx time	—	13	—	ns
9	t_{SUI}	CC	D	Data setup time for inputs	Master (MTFE = 0)	35	—	ns
					Slave	4	—	
					Master (MTFE = 1, CPHA = 0)	35	—	
					Master (MTFE = 1, CPHA = 1)	35	—	
10	t_{HI}	CC	D	Data hold time for inputs	Master (MTFE = 0)	–5	—	ns
					Slave	4	—	
					Master (MTFE = 1, CPHA = 0)	11	—	
					Master (MTFE = 1, CPHA = 1)	–5	—	



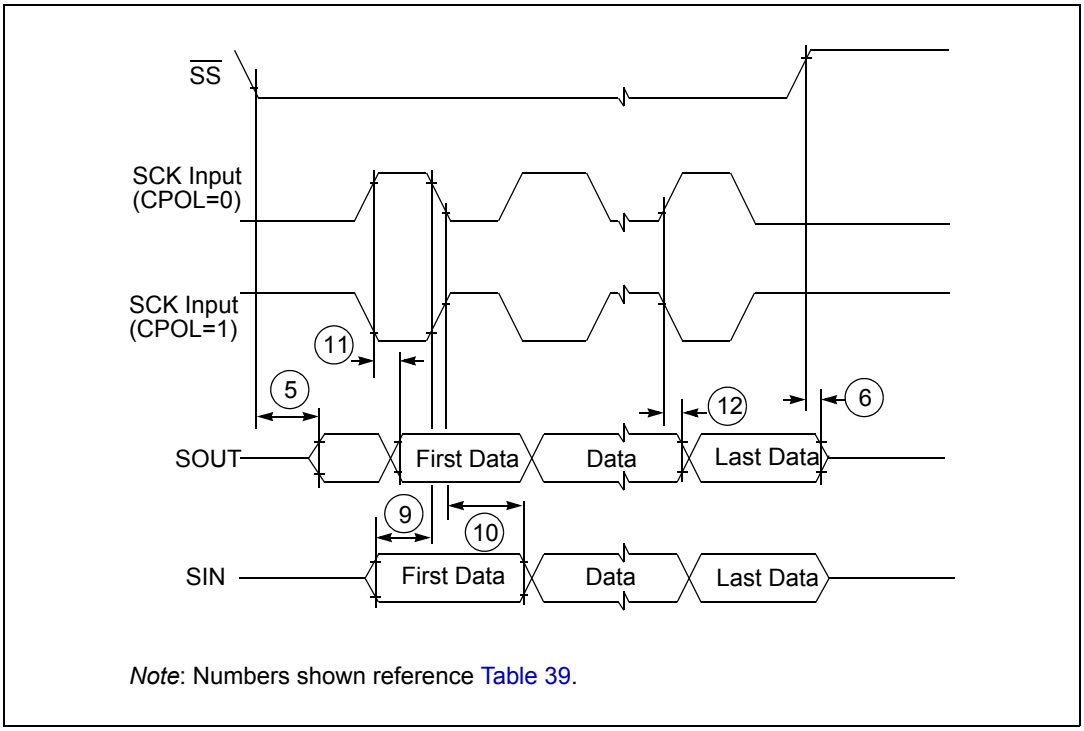
Note: Numbers shown reference Table 39.

Figure 30. DSPI classic SPI timing – Slave, CPHA = 1



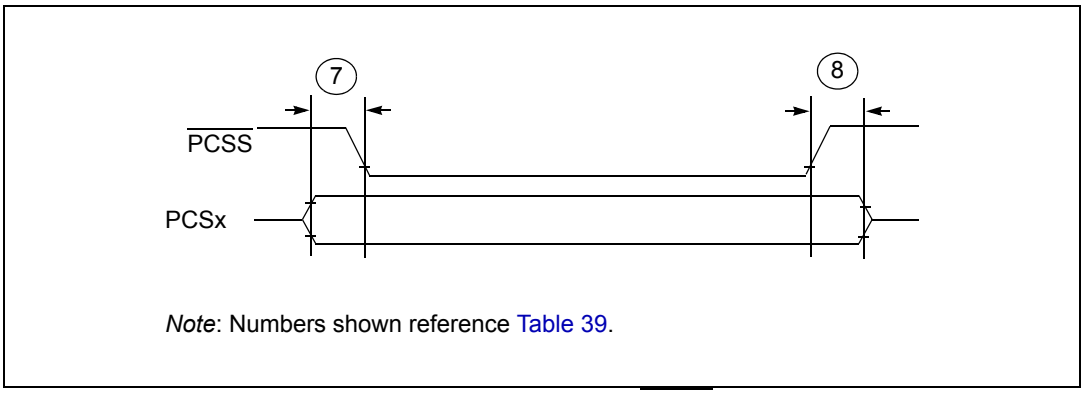
Note: Numbers shown reference Table 39.

Figure 31. DSPI modified transfer format timing – Master, CPHA = 0



Note: Numbers shown reference Table 39.

Figure 34. DSPI modified transfer format timing – Slave, CPHA = 1



Note: Numbers shown reference Table 39.

Figure 35. DSPI PCS Strobe (PCSS) timing

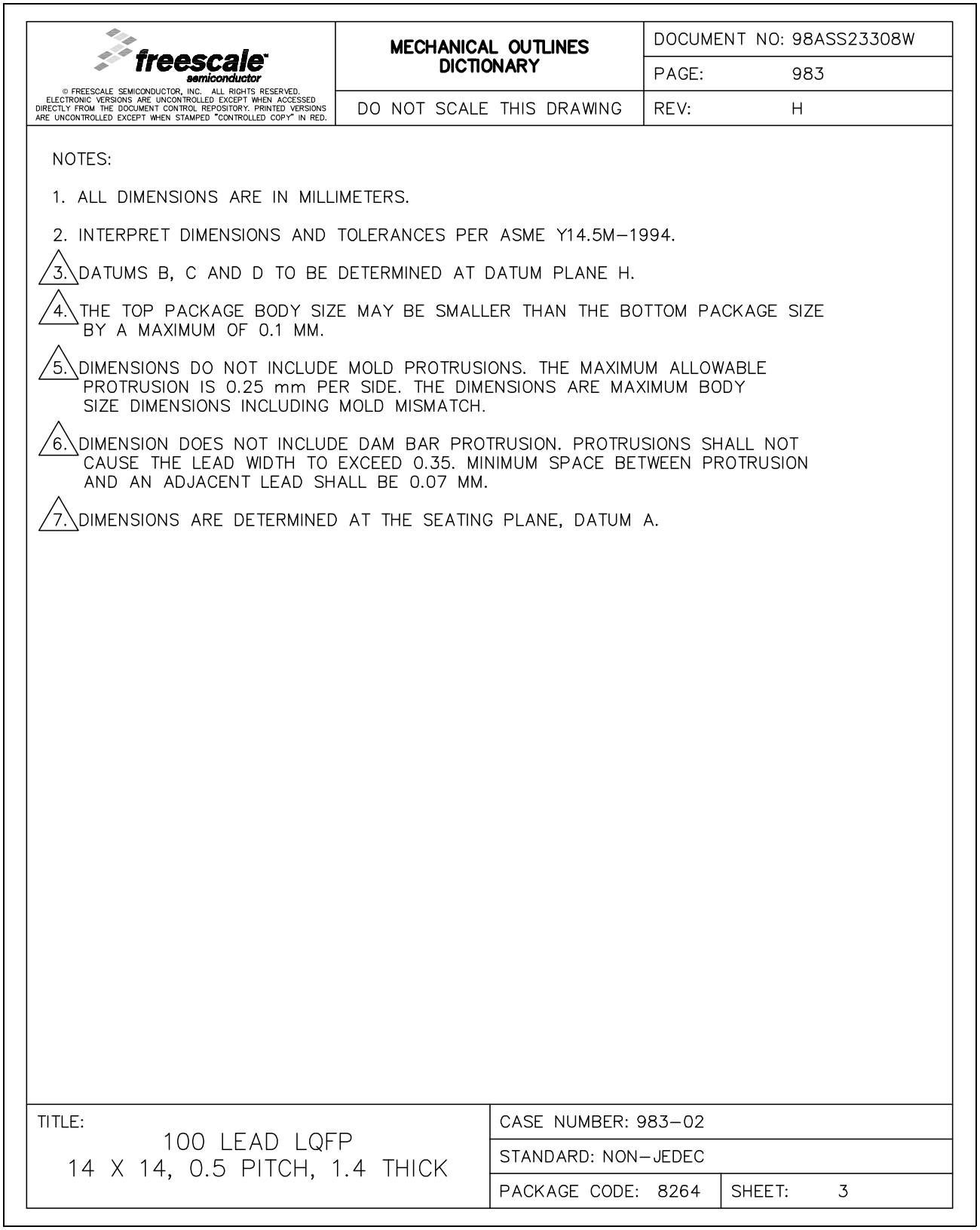


Figure 38. 100 LQFP package mechanical drawing (part 3)